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## Dual 2.5 Gbps 2:1/1:2 CML Mux/Buffer with Transmit PreEmphasis and Receive Equalization

## General Description

The DS25MB200 is a dual signal conditioning 2:1 multiplexer and 1:2 fan-out buffer designed for use in backplane redundancy applications. Signal conditioning features include input equalization and programmable output pre-emphasis that enable data communication in FR4 backplanes up to 2.5 Gbps . Each input stage has a fixed equalizer to reduce ISI distortion from board traces. All output drivers have 4 selectable steps of pre-emphasis to compensate for transmission losses from long FR4 backplanes and reduce deterministic jitter. The preemphasis levels can be independently controlled for the lineside and switch-side drivers. The internal loopback paths from switch-side input to switch-side output enable at-speed system testing. All receiver inputs are internally terminated with $100 \Omega$ differential terminating resistors. All drivers are internally terminated with $50 \Omega$ to $\mathrm{V}_{\mathrm{CC}}$.

## Features

- 0.6-2.5 Gbps low jitter operation
- Fixed input equalization
- Programmable output pre-emphasis
- Independent switch and line side pre-emphasis controls
- Programmable switch-side loopback modes
- On-chip terminations
- HBM ESD rating 6 kV on all pins

■ +3.3V supply

- Lead-less LLP-48 package ( $7 \mathrm{~mm} \times 7 \mathrm{~mm} \times 0.8 \mathrm{~mm}, 0.5 \mathrm{~mm}$ pitch)
- $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ operating temperature range


## Applications

- Backplane or cable driver
- Redundancy and signal conditioning applications


## Functional Block Diagram



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## Simplified Block Diagram



## Connection Diagram



| Pin Name | Pin Number | I/O | Description |  |
| :--- | :---: | :---: | :--- | :--- |
| LINE SIDE HIGH SPEED DIFFERENTIAL IO's |  |  |  |  |
| LI_0+ | 6 | I | Inverting and non-inverting differential inputs of port_0 at the line side. LI_0+ and LI_0- have an <br> LI_0- | 7 |
| internal $50 \Omega$ connected to an internal reference voltage. See Figure 6. |  |  |  |  |
| LO_0+ | 33 | O | Inverting and non-inverting differential outputs of port_0 at the line side. LO_0+ and LO_0- have |  |
| LO_0- | 34 |  | an internal $50 \Omega$ connected to V ${ }_{\text {CC }}$ - |  |
| LI_1+ | 30 | I | Inverting and non-inverting differential inputs of port_1 at the line side. LI_1+ and LI_1- have an |  |
| LI_1- | 31 |  | internal $50 \Omega$ connected to an internal reference voltage. See Figure 6. |  |
| LO_1+ | 9 | O | Inverting and non-inverting differential outputs of port_1 at the line side. LO_1+ and LO_1- have |  |
| LO_1- | 10 |  | an internal $50 \Omega$ connected to $\mathrm{V}_{\text {CC }}$. |  |

SWITCH SIDE HIGH SPEED DIFFERENTIAL IO's

| SOA_0+ | 46 | O | Inverting and non-inverting differential outputs of mux_0 at the switch_A side. SOA_0+ and SOA_0 <br> SOA_0- |
| :--- | :---: | :---: | :--- |
| - have an internal $50 \Omega$ connected to $V_{\text {CC }}$. |  |  |  |

CONTROL (3.3V LVCMOS)

| MUX_S0 | 37 | 1 | A logic low at MUX_S0 selects mux_0 to switch B. MUX_S0 is internally pulled high. Default state for mux_0 is switch A. |
| :---: | :---: | :---: | :---: |
| MUX_S1 | 13 | 1 | A logic low at MUX_S1 selects mux_1 to switch B. MUX_S0 is internally pulled high. Default state for mux_1 is switch A. |
| PREL_0 PREL_1 | $\begin{gathered} 12 \\ 1 \end{gathered}$ | 1 | PREL_0 and PREL_1 select the output pre-emphasis of the line side drivers (LO_0 $\pm$ and LO_1 $\pm$ ). PREL_0 and PREL_1 are internally pulled high. See Table 3 for line side pre-emphasis levels. |
| $\begin{aligned} & \hline \text { PRES_0 } \\ & \text { PRES_1 } \end{aligned}$ | $\begin{aligned} & 36 \\ & 25 \end{aligned}$ | 1 | PRES_0 and PRES_1 select the output pre-emphasis of the switch side drivers (SOA_0 $\pm$, SOB_0 $\pm$, SOA_1 $\pm$ and SOB_1 $\pm$ ). PRES_0 and PRES_1 are internally pulled high. See Table 4 for switch side pre-emphasis levels. |
| LB0A | 47 | 1 | A logic low at LBOA enables the internal loopback path from SIA_0 to SOA_0 $\pm$. LBOA is internally pulled high. |
| LBOB | 48 | 1 | A logic low at LBOB enables the internal loopback path from SIB_0 $\pm$ to SOB_0 $\pm$. LBOB is internally pulled high. |
| LB1A | 23 | 1 | A logic low at LB1A enables the internal loopback path from SIA_1 $\pm$ to SOA_1 $\pm$. LB1A is internally pulled high. |
| LB1B | 24 | 1 | A logic low at LB1B enables the internal loopback path from SIB_1 $\pm$ to SOB_1 $\pm$. LB1B is internally pulled high. |
| RSV | 26 | 1 | Reserve pin to support factory testing. This pin can be left open, or tied to GND, or tied to GND through an external pull-down resistor. |


| Pin Name | Pin Number | I/O | Description |
| :---: | :---: | :---: | :---: |
| POWER |  |  |  |
| $\mathrm{V}_{\text {CC }}$ | $\begin{gathered} 2,8,14,20, \\ 29,35,38, \\ 44 \end{gathered}$ | P | $V_{C C}=3.3 V \pm 5 \%$ <br> Each $\mathrm{V}_{\mathrm{CC}}$ pin should be connected to the $\mathrm{V}_{\mathrm{CC}}$ plane through a low inductance path, typically with a via located as close as possible to the landing pad of the $\mathrm{V}_{C C}$ pin. <br> It is recommended to have a $0.01 \mu \mathrm{~F}$ or $0.1 \mu \mathrm{~F}, \mathrm{X} 7 \mathrm{R}$, size-0402 bypass capacitor from each $\mathrm{V}_{\mathrm{CC}}$ pin to ground plane. |
| GND | $\begin{gathered} 5,11,17,32, \\ 41 \end{gathered}$ | P | Ground reference. Each ground pin should be connected to the ground plane through a low inductance path, typically with a via located as close as possible to the landing pad of the GND pin. |
| GND | DAP | P | Die Attach Pad (DAP) is the metal contact at the bottom side, located at the center of the LLP-48 package. It should be connected to the GND plane with at least 4 via to lower the ground impedance and improve the thermal performance of the package. |

Note: $\mathrm{I}=$ Input, $\mathrm{O}=$ Output, $\mathrm{P}=$ Power
Note: All CML Inputs or Outputs must be AC coupled.

## Functional Description

The DS25MB200 is a signal conditioning 2:1 multiplexer and a $1: 2$ buffer designed to support port redundancy up to 2.5 Gbps. The high speed inputs are self-biased to about 1.3 V and are designed for AC coupling, see Figure 6 for details.. The inputs are compatible to most AC coupling differential signals such as LVDS, LVPECL and CML. The DS25MB200 is not designed to operate with data rates below 250 Mbps or with a DC bias applied to the CML inputs or outputs. Most high speed links are encoded for DC balance and have been defined to include AC coupling capacitors allowing the DS25MB200 to be directly inserted into the datapath without any limitation. The ideal AC coupling capacitor value is often based on the lowest frequency component embedded within the serial link. A typical AC coupling capacitor value ranges between 100 and 1000 nF , some specifications with scrambled data may require a larger capacitor for optimal performance. To reduce unwanted parasitics around and within the AC coupling capacitor, a body size of 0402 is recommended.

Figure 5 shows the AC coupling capacitor placement in an AC test circuit.
Each input stage has a fixed equalizer that provides equalization to compensate about 5 dB of transmission loss from a short backplane trace (about 10 inches backplane). The output driver has Pre-emphasis (driver-side equalization) to compensate the transmission loss of the backplane that it is driving. The driver conditions the output signal such that the lower frequency and higher frequency pulses reach approximately the same amplitude at the end of the backplane, and minimize the deterministic jitter caused by the amplitude disparity. The DS25MB200 provides four steps of user-selectable Pre-emphasis ranging from $0,-3,-6$ and -9 dB to handle different lengths of backplane. Figure 1 shows a driver Pre-emphasis waveform. The Pre-emphasis duration is 188ps nominal, corresponds to 0.47 bit-width at 2.5 Gbps . The Pre-emphasis levels of switch-side and line-side can be individually programmed.

TABLE 1. LOGIC TABLE FOR MULTIPLEX CONTROLS

| MUX_S0 | Mux Function |
| :--- | :--- |
| 0 | MUX_0 select switch_B input, SIB_0 $\pm$. |
| 1 (default) | MUX_0 select switch_A input, SIA_0 $\pm$. |
| MUX_S1 | Mux Function |
| 0 | MUX_1 select switch_B input, SIB_1 $\pm$. |
| 1 (default) | MUX_1 select switch_A input, SIA_0 $\pm$. |

TABLE 2. LOGIC TABLE FOR LOOPBACK CONTROLS

| LBOA | Loopback Function |
| :--- | :--- |
| 0 | Enable loopback from SIA_0 $\pm$ to SOA_0 $\pm$. |
| 1 (default) | Normal mode. Loopback disabled. |
| LB0B | Loopback Function |
| 0 | Enable loopback from SIB_0 $\pm$ to SOB_0 $\pm$. |
| 1 (default) | Normal mode. Loopback disabled. |
| LB1A | Loopback Function |
| 0 | Enable loopback from SIA_1 $\pm$ to SOA_1 $\pm$. |
| 1 (default) | Normal mode. Loopback disabled. |
| LB1B | Loopback Function |
| 0 | Enable loopback from SIB_1 $\pm$ to SOB_1 $\pm$. |
| 1 (default) | Normal mode. Loopback disabled. |

TABLE 3. LINE-SIDE PRE-EMPHASIS CONTROLS

| PreL_[1:0] | Pre-Emphasis Level in <br> $\mathbf{m V}_{\mathbf{P P}}$ <br> (VODB) | De-Emphasis Level <br> in $\mathbf{~ m ~}_{\mathbf{P P}}$ <br> (VODPE) | Pre-Emphasis in dB <br> (VODPE/VODB) | Typical FR4 board <br> trace |
| :---: | :---: | :---: | :---: | :--- |
| 00 | 1200 | 1200 | 0 | 10 inches |
| 01 | 1200 | 849.53 | -3 | 20 inches |
| 10 | 1200 | 600 | -6 | 30 inches |
| 11 (default) | 1200 | 425.78 | -9 | 40 inches |

TABLE 4. SWITCH-SIDE PRE-EMPHASIS CONTROLS

| PreS_[1:0] | Pre-Emphasis Level in <br> $\mathbf{m V}_{\mathbf{P P}}$ <br> (VODB) | De-Emphasis Level <br> in $\mathbf{~} \mathbf{V V}_{\mathbf{P P}}$ <br> (VODPE) | Pre-Emphasis in dB <br> (VODPE/VODB) | Typical FR4 board <br> trace |
| :---: | :---: | :---: | :---: | :--- |
| 00 | 1200 | 1200 | 0 | 10 inches |
| 01 | 1200 | 849.53 | -3 | 20 inches |
| 10 | 1200 | 600 | -6 | 30 inches |
| 11 (default) | 1200 | 425.78 | -9 | 40 inches |



FIGURE 1. Driver Pre-Emphasis Differential Waveform (showing all 4 pre-emphasis steps)

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Absolute Maximum Ratings (Note 1)
If Military/Aerospace specified devices are required,
please contact the National Semiconductor Sales Office/
Distributors for availability and specifications.
\begin{tabular}{lr} 
Supply Voltage \(\left(\mathrm{V}_{\mathrm{CC}}\right)\) & -0.3 V to 4 V \\
CMOS/TTL Input Voltage & -0.3 V to \\
& \(\left(\mathrm{V}_{\mathrm{CC}}+0.3 \mathrm{~V}\right)\) \\
CML Input/Output Voltage & -0.3 V to \\
& \(\left(\mathrm{V}_{\mathrm{CC}}+0.3 \mathrm{~V}\right)\) \\
Junction Temperature & \(+150^{\circ} \mathrm{C}\) \\
Storage Temperature & \(-65^{\circ} \mathrm{C}\) to \(+150^{\circ} \mathrm{C}\) \\
Lead Temperature & \(+260^{\circ} \mathrm{C}\) \\
\(\quad\) Soldering, 4 sec & \(33.7^{\circ} \mathrm{C} / \mathrm{W}\)
\end{tabular}
```

| Thermal Resistance, $\theta_{\text {JC-top }}$ | $20.7^{\circ} \mathrm{C} / \mathrm{W}$ |
| :--- | ---: |
| Thermal Resistance, $\theta_{\mathrm{JC} \text {-bottom }}$ | $5.8^{\circ} \mathrm{C} / \mathrm{W}$ |
| Thermal Resistance, $\Phi_{\mathrm{JB}}$ | $18.2^{\circ} \mathrm{C} / \mathrm{W}$ |
| ESD Rating HBM, $1.5 \mathrm{k} \Omega, 100 \mathrm{pF}$ | 6 kV |

## Recommended Operating Ratings

## Electrical Characteristics

Over recommended operating supply and temperature ranges unless otherwise specified.

| Symbol | Parameter | Conditions | Min | $\begin{gathered} \text { Typ } \\ \text { (Note 2) } \end{gathered}$ | Max | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| LVCMOS DC SPECIFICATIONS |  |  |  |  |  |  |
| $\mathrm{V}_{\mathrm{IH}}$ | High Level Input Voltage |  | 2.0 |  | $\mathrm{V}_{\mathrm{CC}}+0.3$ | V |
| $\mathrm{V}_{\text {IL }}$ | Low Level Input Voltage |  | -0.3 |  | 0.8 | V |
| $\mathrm{I}_{\mathrm{H}}$ | High Level Input Current | $\mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{CC}}$ | -10 |  | 10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {IL }}$ | Low Level Input Current | $\mathrm{V}_{\text {IN }}=\mathrm{GND}$ | 75 | 94 | 124 | $\mu \mathrm{A}$ |
| $\mathrm{R}_{\text {PU }}$ | Pull-High Resistance |  |  | 35 |  | $\mathrm{k} \Omega$ |
| RECEIVER SPECIFICATIONS |  |  |  |  |  |  |
| $\mathrm{V}_{\text {ID }}$ | Differential Input Voltage Range | AC Coupled Differential Signal Below 1.25 Gbps Above 1.25 Gbps Measured at input pins. | $\begin{aligned} & 100 \\ & 100 \end{aligned}$ |  | $\begin{aligned} & 1750 \\ & 1560 \end{aligned}$ | $\begin{aligned} & m V_{P-P} \\ & m V_{P-P} \end{aligned}$ |
| $\mathrm{V}_{\text {ICM }}$ | Common Mode Voltage at Receiver Inputs | Measured at receiver inputs reference to ground. |  | 1.5 |  | V |
| $\mathrm{R}_{\text {ITD }}$ | Input Differential Termination | On-chip differential termination between IN+ or IN -. | 84 | 100 | 116 | $\Omega$ |
| DRIVER SPECIFICATIONS |  |  |  |  |  |  |
| VODB | Output Differential Voltage Swing without Pre-Emphasis | $\begin{aligned} & \hline \mathrm{R}_{\mathrm{L}}=100 \Omega \pm 1 \% \\ & \text { PRES_1=PRES_0=0 } \\ & \text { PREL_1=PREL_0=0 } \end{aligned}$ <br> Driver pre-emphasis disabled. <br> Running K28.7 pattern at 2.5 Gbps . <br> See Figure 5 for test circuit. | 1000 | 1200 | 1400 | $m V_{\text {P-P }}$ |


| Symbol | Parameter | Conditions | Min | $\begin{gathered} \text { Typ } \\ \text { (Note 2) } \end{gathered}$ | Max | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {PE }}$ | Output Pre-Emphasis Voltage Ratio 20*log(VODPE/VODB) | $R_{L}=100 \Omega \pm 1 \%$ <br> Running K28.7 pattern at 2.5 Gbps <br> PREx_[1:0]=00 <br> PREx_[1:0]=01 <br> PREx_[1:0]=10 <br> PREx_[1:0]=11 <br> $\mathrm{x}=\mathrm{S}$ for switch side pre-emphasis control $\mathrm{x}=\mathrm{L}$ for line side pre-emphasis control <br> See Figure 1 on waveform. <br> See Figure 5 for test circuit. |  | $\begin{gathered} 0 \\ -3 \\ -6 \\ -9 \end{gathered}$ |  | $\begin{aligned} & \mathrm{dB} \\ & \mathrm{~dB} \\ & \mathrm{~dB} \\ & \mathrm{~dB} \end{aligned}$ |
| $t_{\text {PE }}$ | Pre-Emphasis Width | Tested at -9 dB pre-emphasis level, PREx[1:0]=11 <br> $\mathrm{x}=\mathrm{S}$ for switch side pre-emphasis control <br> $x=L$ for line side pre-emphasis control <br> See Figure 4 on measurement condition. | 125 | 188 | 400 | ps |
| $\mathrm{R}_{\text {OTSE }}$ | Output Termination | On-chip termination from OUT+ or OUT- to $\mathrm{V}_{\text {cc }}$ | 42 | 50 | 58 | $\Omega$ |
| $\mathrm{R}_{\text {OTD }}$ | Output Differential Termination | On-chip differential termination between OUT+ and OUT- |  | 100 |  | $\Omega$ |
| $\Delta \mathrm{R}_{\text {OTSE }}$ | Mis-Match in Output Termination Resistors | Mis-match in output terminations at OUT+ and OUT- |  |  | 5 | \% |
| $\mathrm{V}_{\text {OCM }}$ | Output Common Mode Voltage |  | 2.4 |  | 2.9 | V |
| POWER DISSIPATION |  |  |  |  |  |  |
| $\mathrm{P}_{\mathrm{D}}$ | Power Dissipation | $V_{D D}=3.465 \mathrm{~V}$ <br> All outputs terminated by $100 \Omega \pm 1 \%$. <br> PREL_[1:0]=0, PRES_[1:0]=0 <br> Running PRBS ${ }^{7}-1$ pattern at 2.5 Gbps |  |  | 1 | W |

## AC CHARACTERISTICS

| $\mathrm{t}_{\mathrm{R}}$ | Differential Low to High Transition Time | Measured with a clock-like pattern at 100 MHz , between $20 \%$ and $80 \%$ of the differential output |  | 80 |  | ps |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{t}_{\mathrm{F}}$ | Differential High to Low Transition Time | voltage. Pre-emphasis disabled. <br> Transition time is measured with fixture as shown in Figure 5, adjusted to reflect the transition time at the output pins. |  | 80 |  | ps |
| $\mathrm{t}_{\text {PLH }}$ | Differential Low to High Propagation Delay | Measured at $50 \%$ differential voltage from input to output. |  | 0.5 | 2 | ns |
| $\mathrm{t}_{\text {PHL }}$ | Differential High to Low Propagation Delay |  |  | 0.5 | 2 | ns |
| $\mathrm{t}_{\text {SKP }}$ | Pulse Skew | $\left\|\mathrm{It}_{\text {PHL }}-\mathrm{t}_{\text {PLH }}\right\|$ |  |  | 20 | ps |
| $\mathrm{t}_{\text {SKO }}$ | Output Skew (Note 7) | Difference in propagation delay between two outputs in the same device. |  |  | 200 | ps |
| $\mathrm{t}_{\text {SKPP }}$ | Part-to-Part Skew | Difference in propagation delay between the same output from devices operating under identical conditions. |  |  | 500 | ps |
| $\mathrm{t}_{\mathrm{SM}}$ | Mux Switch Time | Measured from $\mathrm{V}_{\mathrm{IH}}$ or $\mathrm{V}_{\mathrm{IL}}$ of the mux-control or loopback control to $50 \%$ of the valid differential output. |  | 1.8 | 6 | ns |
| RJ | Device Random Jitter (Note 5) | See Figure 5 for test circuit. Alternating-1-0 pattern. Pre-emphasis disabled. <br> At 1.25 Gbps <br> At 2.5 Gbps |  |  | $\begin{aligned} & 2 \\ & 2 \end{aligned}$ | psrms psrms |


| Symbol | Parameter | Conditions | Min | Typ <br> (Note 2) | Max | Units |
| :--- | :--- | :--- | :---: | :---: | :---: | :---: |
| DJ | Device Deterministic <br> Jitter (Note 6) | See Figure 5 for test circuit. <br> Pre-emphasis disabled. <br> Between 0.8 and 2.5 Gbps with PRBS7 pattern for <br> DS25MB200 @ $-40^{\circ} \mathrm{C}$ to $85^{\circ} \mathrm{C}$ |  |  |  |  |
| $\mathrm{DR}_{\text {MAX }}$ | Maximum Data Rate | Tested with alternating 1-0 pattern <br> (Note 8) | 2.5 |  | 30 | Pspp |
| $\mathrm{DR}_{\text {MIN }}$ | Minimum Data Rate |  |  |  | 0.6 | Gbps |

Note 1: "Absolute Maximum Ratings" are the ratings beyond which the safety of the device cannot be guaranteed. They are not meant to imply that the device should be operated at these limits.
Note 2: Typical parameters measured at $\mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$. They are for reference purposes and are not production-tested.
Note 3: IN+ and IN- are generic names refer to one of the many pairs of complimentary inputs of the DS25MB200. OUT+ and OUT- are generic names refer to one of the many pairs of the complimentary outputs of the DS25MB200. Differential input voltage $\mathrm{V}_{\mathrm{ID}}$ is defined as IIN+-IN-I. Differential output voltage $\mathrm{V}_{\mathrm{OD}}$ is defined as IOUT+-OUT-I.
Note 4: K28.7 pattern is a 10-bit repeating pattern of K28.7 code group \{001111 1000\}
K28.5 pattern is a 20-bit repeating pattern of +K28.5 and -K28.5 code groups $\{1100000101001111$ 1010 $\}$
Note 5: Device output random jitter is a measurement of the random jitter contribution from the device. It is derived by the equation sqrt $\left(R J_{O U T}{ }^{2}-R J_{I N}{ }^{2}\right)$, where $R J_{\text {OUT }}$ is the random jitter measured at the output of the device in psrms, $R J_{I N}$ is the random jitter of the pattern generator driving the device.
Note 6: Device output deterministic jitter is a measurement of the deterministic jitter contribution from the device. It is derived by the equation ( $D J_{\text {Out }}-D J_{\text {IN }}$ ), where $D J_{\text {OUT }}$ is the peak-to-peak deterministic jitter measured at the output of the device in $\mathrm{pspp}, ~ D J_{\mathbb{I N}}$ is the peak-to-peak deterministic jitter of the pattern generator driving the device.
Note 7: $\mathrm{t}_{\mathrm{SKO}}$ is the magnitude difference in the propagation delays among data paths between switch A and switch B of the same port and similar data paths between port 0 and port 1 . An example is the output skew among data paths from SIA_0 $\pm$ to LO_O $\pm$, SIB_0 $\pm$ to LO_0 $\pm$, SIA_ $1 \pm$ to LO_ $1 \pm$ and SIB_ $1 \pm$ to LO_ 1
 the delay skew of the loopback paths of the same port and between similar data paths between port 0 and port 1. An example is the output skew among data paths SIA $0 \pm$ to SOA $0 \pm \pm$, SIB_0 $\pm$ to SOB_0 $\pm$, SIA $\_1 \pm$ to SOA_ $1 \pm$ and SIB_1 $\pm$ to SOB_1 $\pm$.
Note 8: For operation under 1 Gbps , encoded data transmission is recommended (i.e. 8b10b).

## Timing Diagrams



FIGURE 2. Driver Output Transition Time


FIGURE 3. Propagation Delay from Input to Output


FIGURE 4. Test Condition for Output Pre-Emphasis Duration


FIGURE 5. AC Test Circuit


FIGURE 6. Receiver Input Termination and Biasing Circuit

## Application Information

The DS25MB200 input equalizer provides equalization to compensate about 5 dB of transmission loss from a short backplane transmission line. For characterization purposes, a 25 -inch FR4 coupled micro-strip board trace is used in place
of the short backplane link. The 25 -inch microstrip board trace has approximately 5 dB of attenuation between 375 MHz and 1.875 GHz , representing closely the transmission loss of the short backplane transmission line. The 25 -inch microstrip is connected between the pattern generator and the differential inputs of the DS25MB200 for AC measurements.

| Trace Length | Finished Trace <br> Width W | Separation between <br> Traces | Dielectric Height H | Dielectric Constant <br> $\varepsilon_{\mathbf{R}}$ | Loss Tangent |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 25 inches | 8.5 mil | 11.5 mil | 6 mil | 3.8 | 0.022 |



FIGURE 7. Application Diagram (showing data paths of port 0 )

Physical Dimensions inches (millimeters) unless otherwise noted


RECOMMENDED LAND PATTERN


DIMENSIONS ARE IN MILLIMETERS
DIMENSIONS IN ARE FOR RE=ERENCE ONLY


LLP-48 Package
Order Number DS25MB200TSQ
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| Email: support@nsc.com |  |  |  |
|  |  |  |  |


[^0]:    Note: All CML inputs and outputs must be AC coupled for optimal performance

